

Scattering effect of the high-index dielectric nanospheres for high performance hydrogenated amorphous silicon thin-film solar cells

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Supplement information

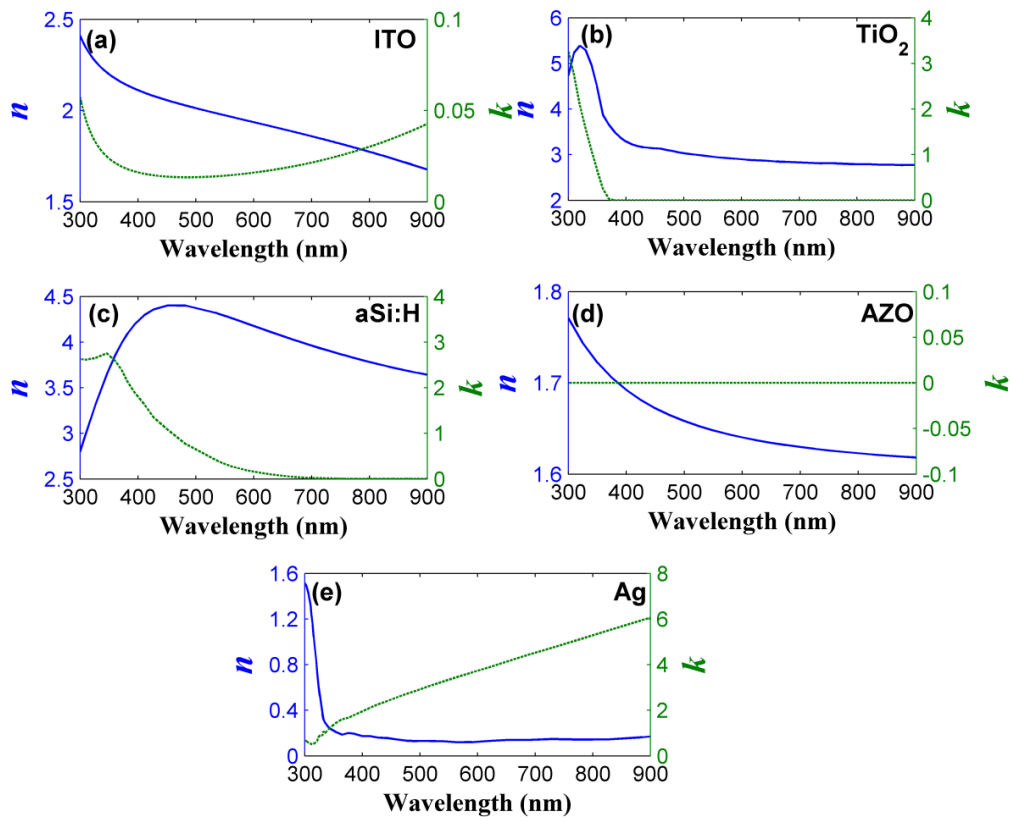


Fig. S1. The refractive index n and extinction coefficient k for (a) ITO, (b) TiO_2 , (c) a-Si:H, (d) AZO, and (e) Ag, respectively.

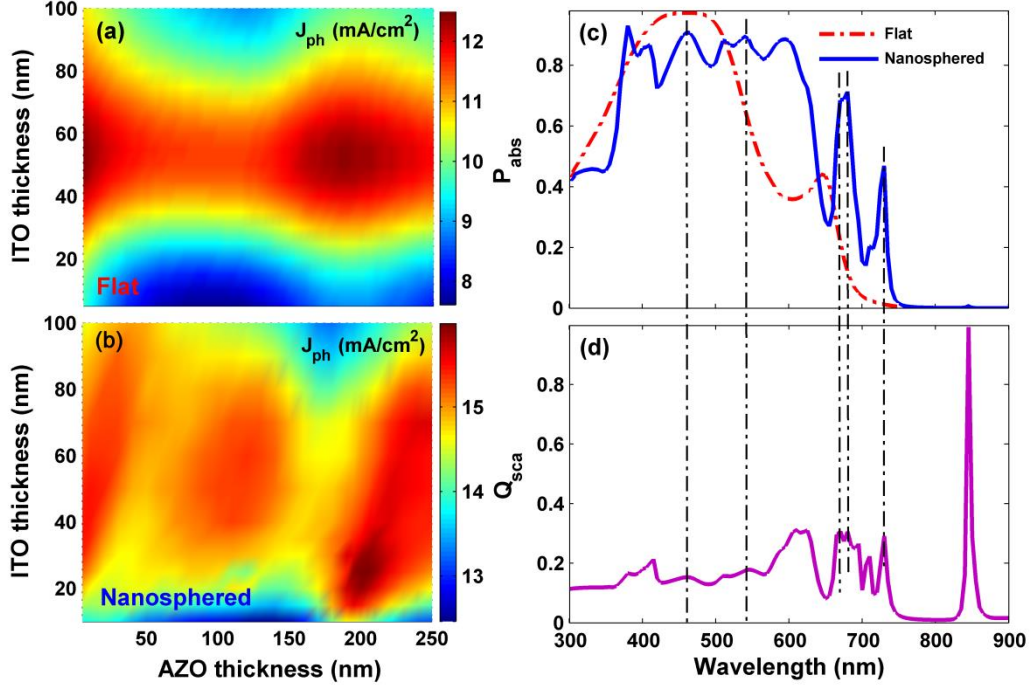


Fig. S2. (a)/(b) photocurrent density (J_{ph}) versus thickness of ITO and AZO for the flat/nanosphered TFSCs, (c) absorption spectra (P_{abs}) under flat and nanosphered designs, and (d) normalized scattering spectrum (Q_{sca}) under TiO₂-nanosphered system.

In this study, on the basic of electromagnetic field distributions, we calculated the scattering efficiency (Q_{sca}) by integrating energy flux densities under the entire surface area of nanosphere. In detail, it can be expressed as the following formulas:

$$Q_{sca} = \iint P_{sca} ds \quad (1)$$

$$P_{sca} = n_x \cdot P_{scax} + n_y \cdot P_{sca y} + n_z \cdot P_{sca z} \quad (2)$$

$$P_{sca x} = \frac{1}{2} \text{Re}(\mathbf{E}_y \times \mathbf{H}_z - \mathbf{E}_z \times \mathbf{H}_y) \quad (3)$$

$$P_{sca y} = \frac{1}{2} \text{Re}(\mathbf{E}_z \times \mathbf{H}_x - \mathbf{E}_x \times \mathbf{H}_z) \quad (4)$$

$$P_{sca z} = \frac{1}{2} \text{Re}(\mathbf{E}_x \times \mathbf{H}_y - \mathbf{E}_y \times \mathbf{H}_x) \quad (5)$$

where n_x , n_y and n_z are the refractive indexes, $P_{sca x}$, $P_{sca y}$ and $P_{sca z}$ are the energy flux densities, E_x , E_y and E_z (H_x , H_y and H_z) are the electric (magnetic) fields along x , y and z directions, respectively. S is the surface area of nanosphere. To well address this problem, we presented the $P_{sca z}$ values with the space angle (in the yz plane) as an example (as shown in Fig. S3).

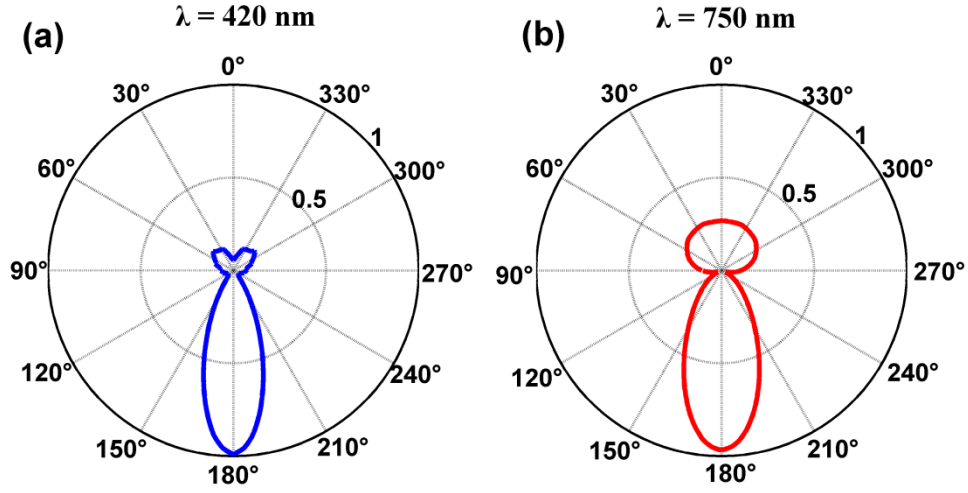


Fig. S3. P_{scaz} as a function of the angle under (a) $\lambda = 420$ nm, and (b) 750 nm, respectively.

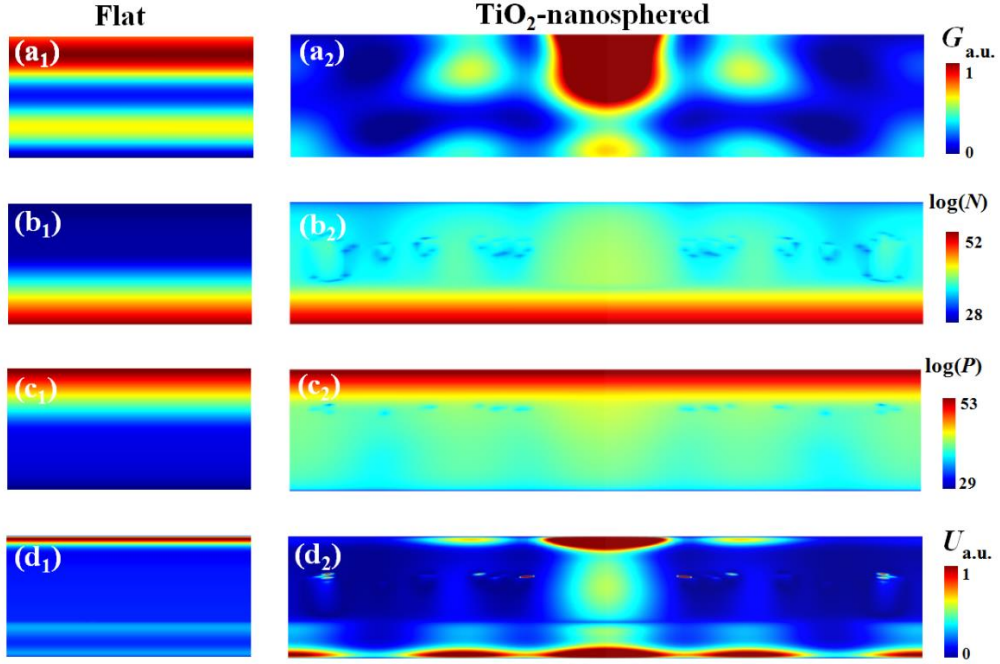


Fig. S4. The spatial distributions of the stabilized carrier generation (a₁)/(a₂), electron concentration (b₁)/(b₂), hole concentration (c₁)/(c₂), and bulk recombination (d₁)/(d₂) inside the a-Si:H layer at the wavelength of 500nm for flat/TiO₂ nanosphered TFSCs, respectively.

The three dimensional (3D) transport equations for electrons and holes in this study can be expressed as:

$$\nabla(-D_n \nabla n + n \mu_n \nabla \Phi) = G - U \quad (6)$$

$$\nabla(-D_p \nabla p - p \mu_p \nabla \Phi) = G - U \quad (7)$$

where n (p) is the electron (hole) concentration, $D_n = \mu_n K_B T / q$ ($D_p = \mu_p K_B T / q$) is the electron (hole) diffusion coefficient, μ_n (μ_p) is the electron (hole) mobility, K_B is Boltzmann's constant, T is the operating temperature, q is the electron charge, Φ is the electrostatic potential. The electrostatic potential Φ is determined by the charge profiles in the device according to the Poisson's equation:

$$\nabla^2 \Phi = \frac{q}{\varepsilon} (n - p - N_d + N_a) \quad (8)$$

where ε is the material permittivity, N_d (N_a) is the concentration of the ionized donor (acceptor). The wavelength-dependent photocarrier generation rate $G(\lambda)$ can be expressed as following formula:

$$G(\lambda) = \frac{\varepsilon''(\lambda) |E(\lambda)|^2}{2\hbar} \Phi_{AM1.5}(\lambda) d\lambda \quad (9)$$

where ε'' is the imaginary part of the permittivity, E is the electric field, and \hbar is the reduced Planck constant. U includes contributions from Shockley-Read-Hall, radiative, and Auger recombinations:

$$U_{\text{bulk}} = U_{\text{SRH}} + U_{\text{Aug}} + U_{\text{Rad}} \quad (10)$$

$$U_{\text{SRH}} = \frac{np - n_i^2}{\tau_n(p + n_i) + \tau_p(n + n_i)} \quad (11)$$

$$U_{\text{Aug}} = (C_n n + C_p p)(np - n_i^2) \quad (12)$$

$$U_{\text{Rad}} = B_{\text{rad}}(np - n_i^2) \quad (13)$$

where τ_n (τ_p) is the electron (hole) lifetime, n_i is the intrinsic carrier concentration, B_{rad} is the coefficient of bimolecular radiative recombination, and C_n (C_p) the electron (hole) Auger coefficient. The short-current density (J_{sc}) is calculated by integrating the EQE spectrum of the cell under the standard AM1.5G illumination.

$$J_{\text{sc}} = \int_{300\text{nm}}^{850\text{nm}} \frac{e\lambda}{hc} \Phi_{AM1.5}(\lambda) EQE(\lambda) d\lambda \quad (14)$$

where e is the unit charge, h the Plank constant, c the speed of light in vacuum, and $\Phi_{AM1.5}$ the solar spectral irradiance under air mass 1.5.

Table. S1 Parameters used in this simulation

Variables	Values	Unit
N_a	1.3×10^{17}	cm^{-3}
N_d	4.3×10^{16}	cm^{-3}
T	300	K
τ_n	1.7 – 2	μs
τ_p	0.34 – 2	μs
μ_n	$4.6 \times 10^{-2} - 1$	cm^2/Vs
μ_p	$9.2 \times 10^{-3} - 0.5$	cm^2/Vs
ε	11.7	
C_n	1×10^{-30}	cm^6/s
C_p	1×10^{-30}	cm^6/s
B_{rad}	7.2×10^{-10}	cm^3/s
n_i	5×10^7	cm^{-3}